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*“The bitterness of poor quality remains long after the sweetness of low price is forgotten.”*

– Benjamin Franklin –



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# The key to Designing Reliable Storage Systems

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VP Marketing & Strategy

EMBD-101-A-1: Embedded Applications, Part 1 – Drive Design



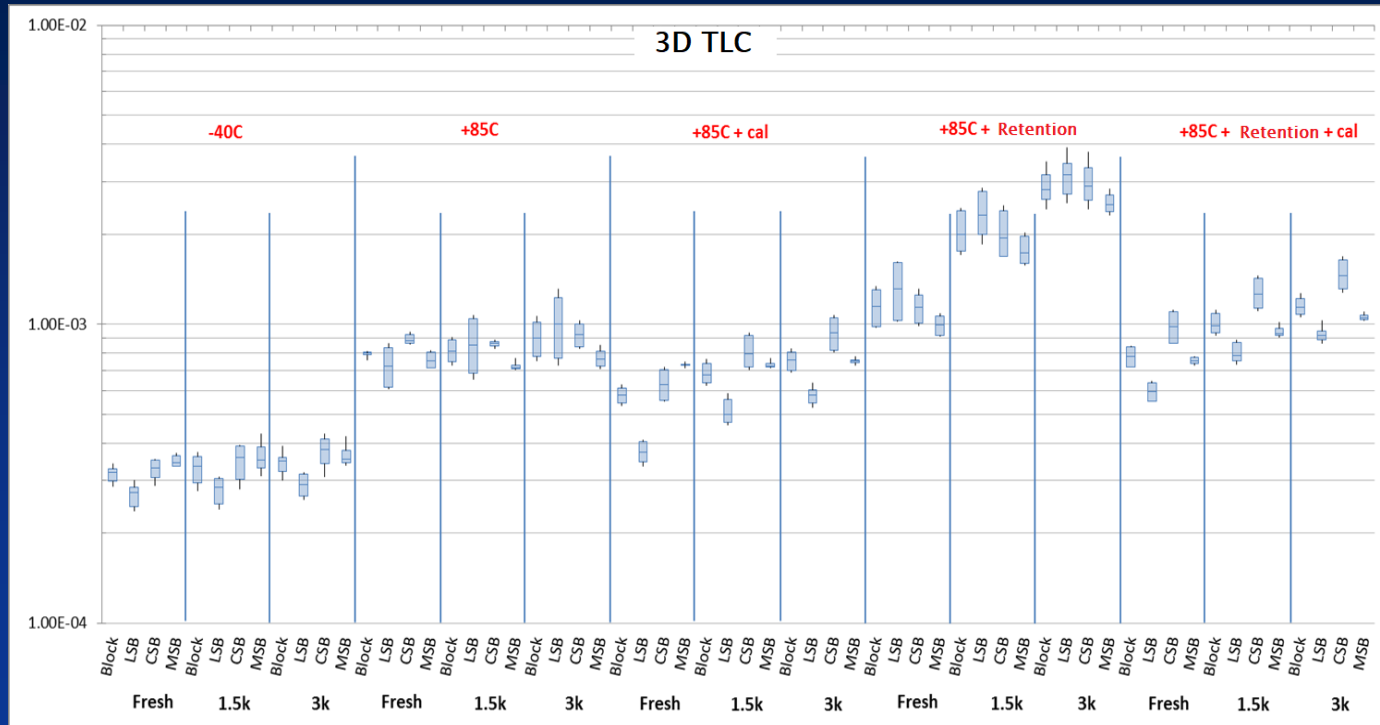


# System Level Reliability

- Some quality needs to be by-design
- Our design and reliability target:  
Highest correction performance with guaranteed error floor
  - UBER at no less than  $1 \times 10^{-16}$  worst case



# Lifetime RBER

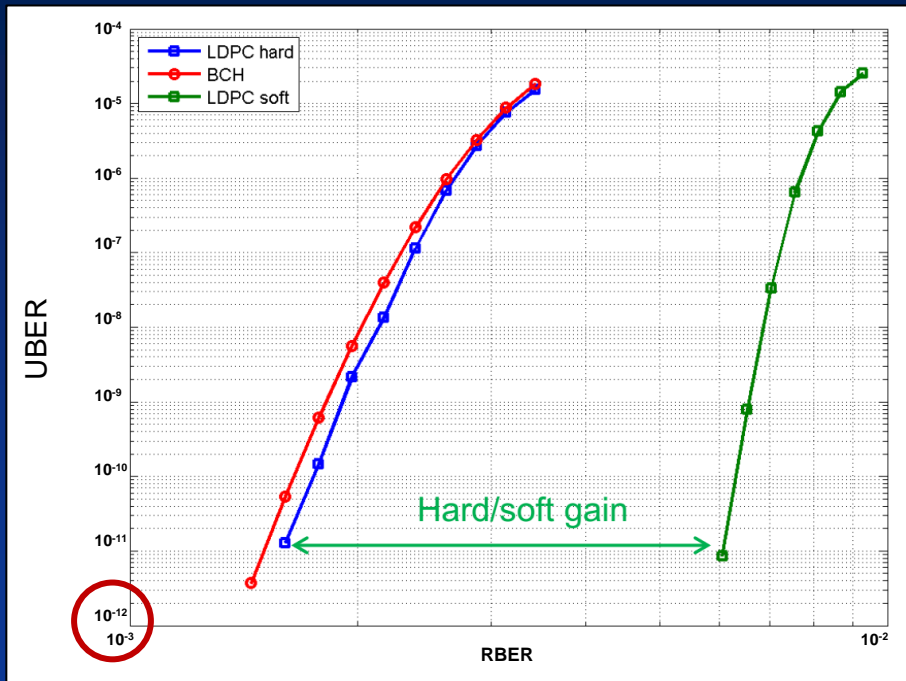


Cross-temp program at  $-40^{\circ}\text{C}$  read at different temperatures

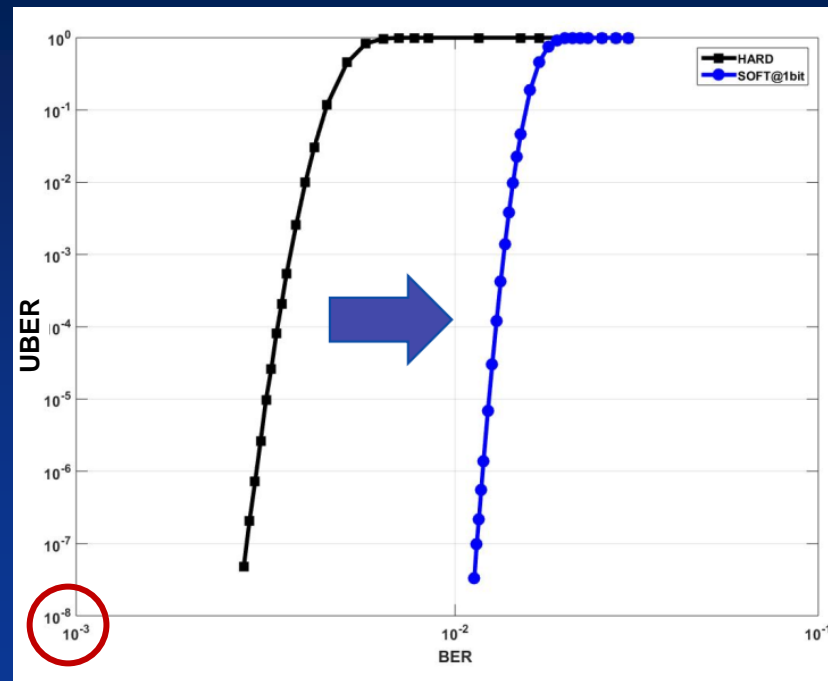
After calibration, RBER between  $2 \times 10^{-4}$  and  $2 \times 10^{-3}$  (EOL & worst case)



# Typical ECC performance plots

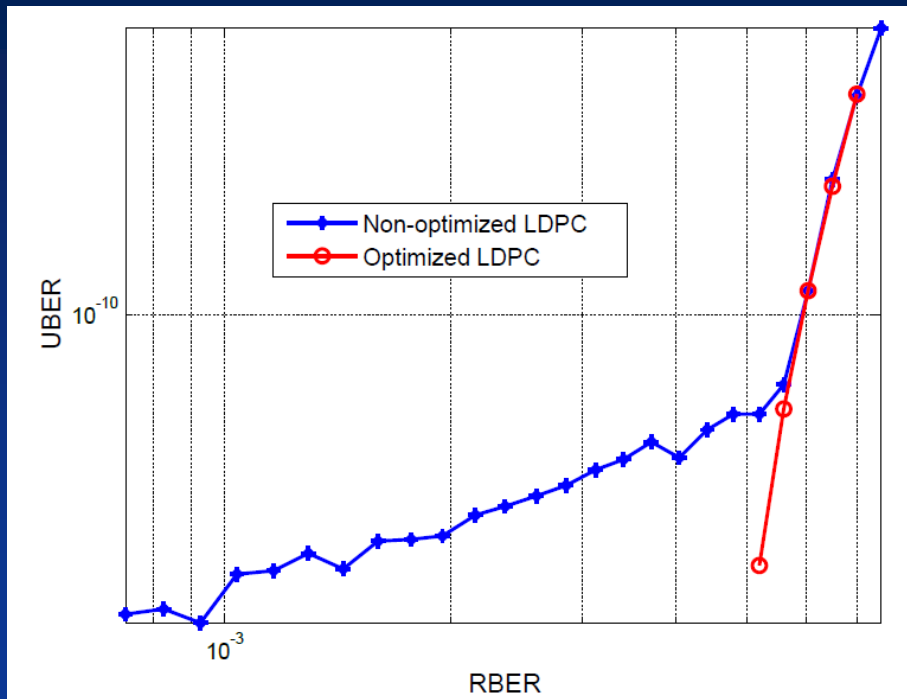


"LDPC Code Concepts and Performance on High-Density Flash Memory", Erich F. Haratsch, Flash Memory Summit 2014

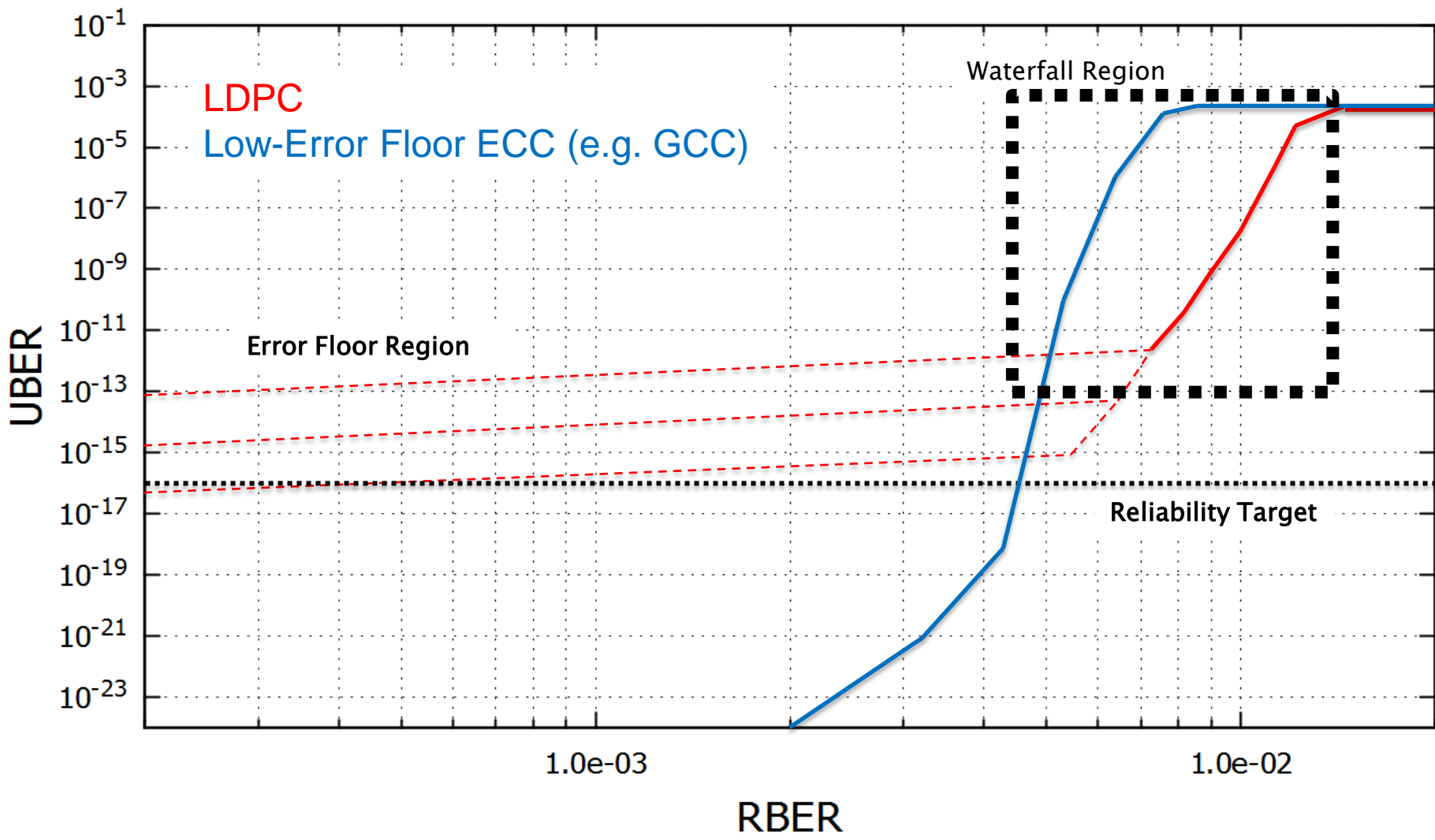


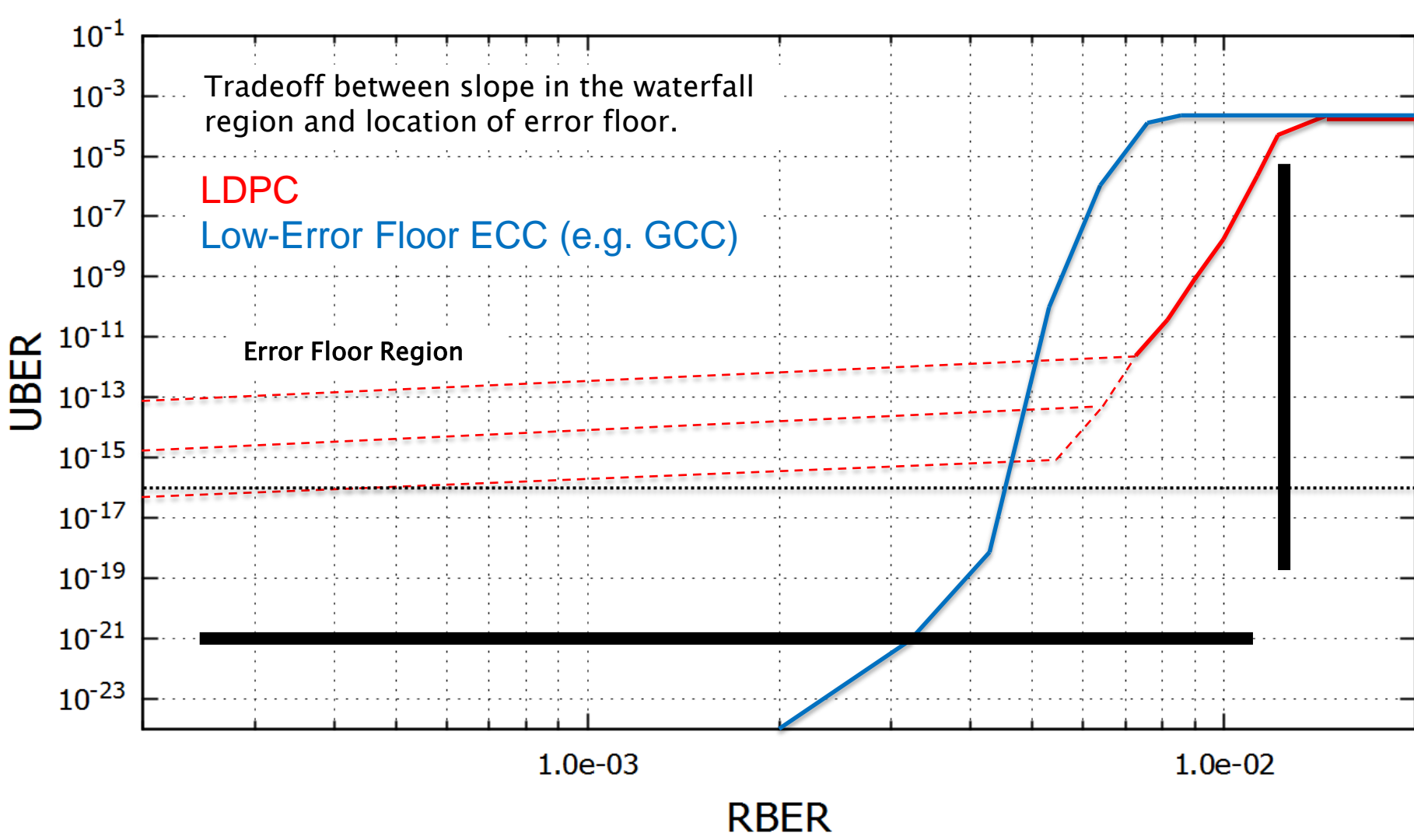
"Fully Integrated LLR Calculation Flow", L. Zuolo, A. Marelli, and R. Micheloni, Flash Memory Summit 2018

# Where exactly is the error floor of the ECC you are using?

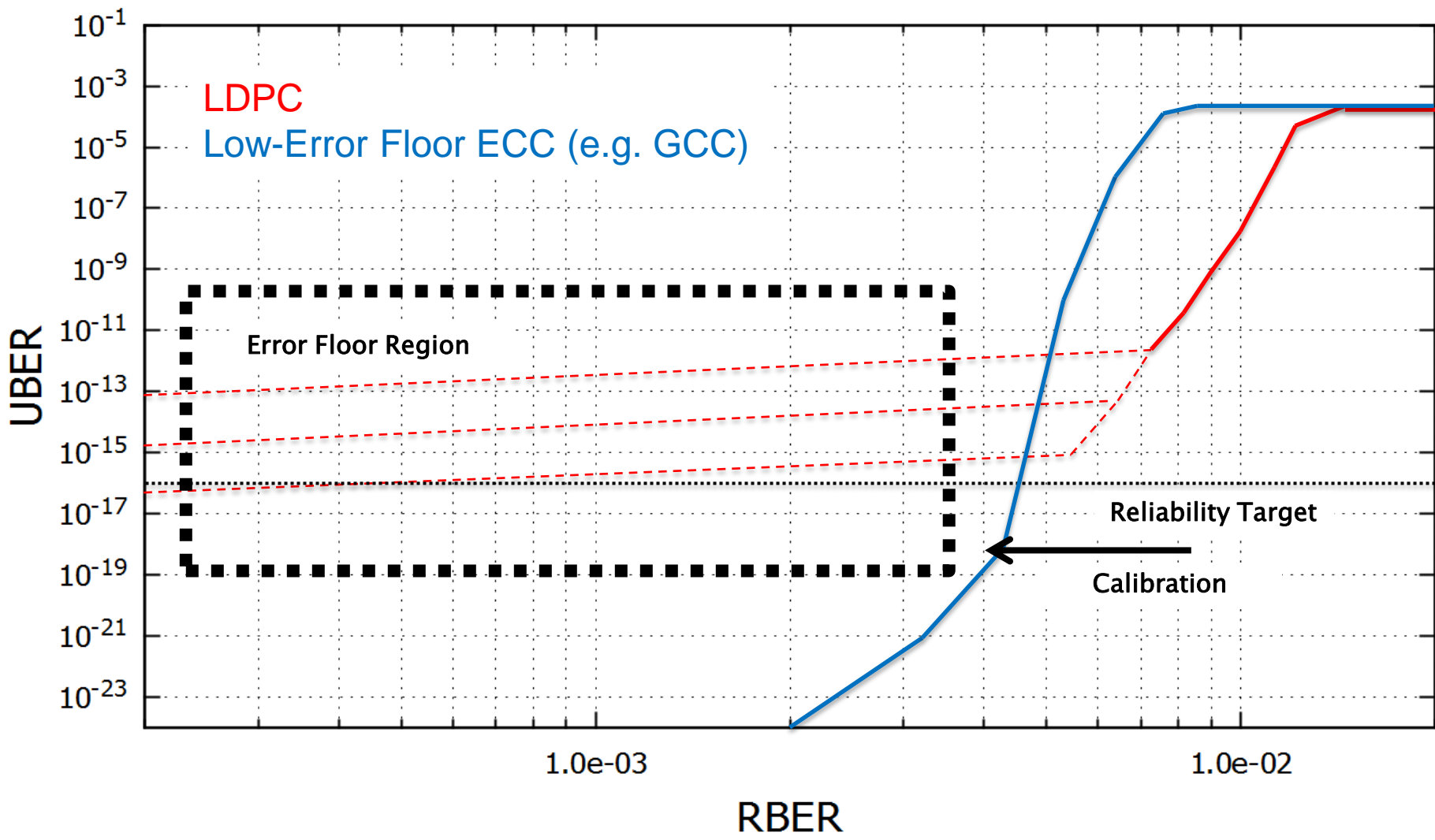


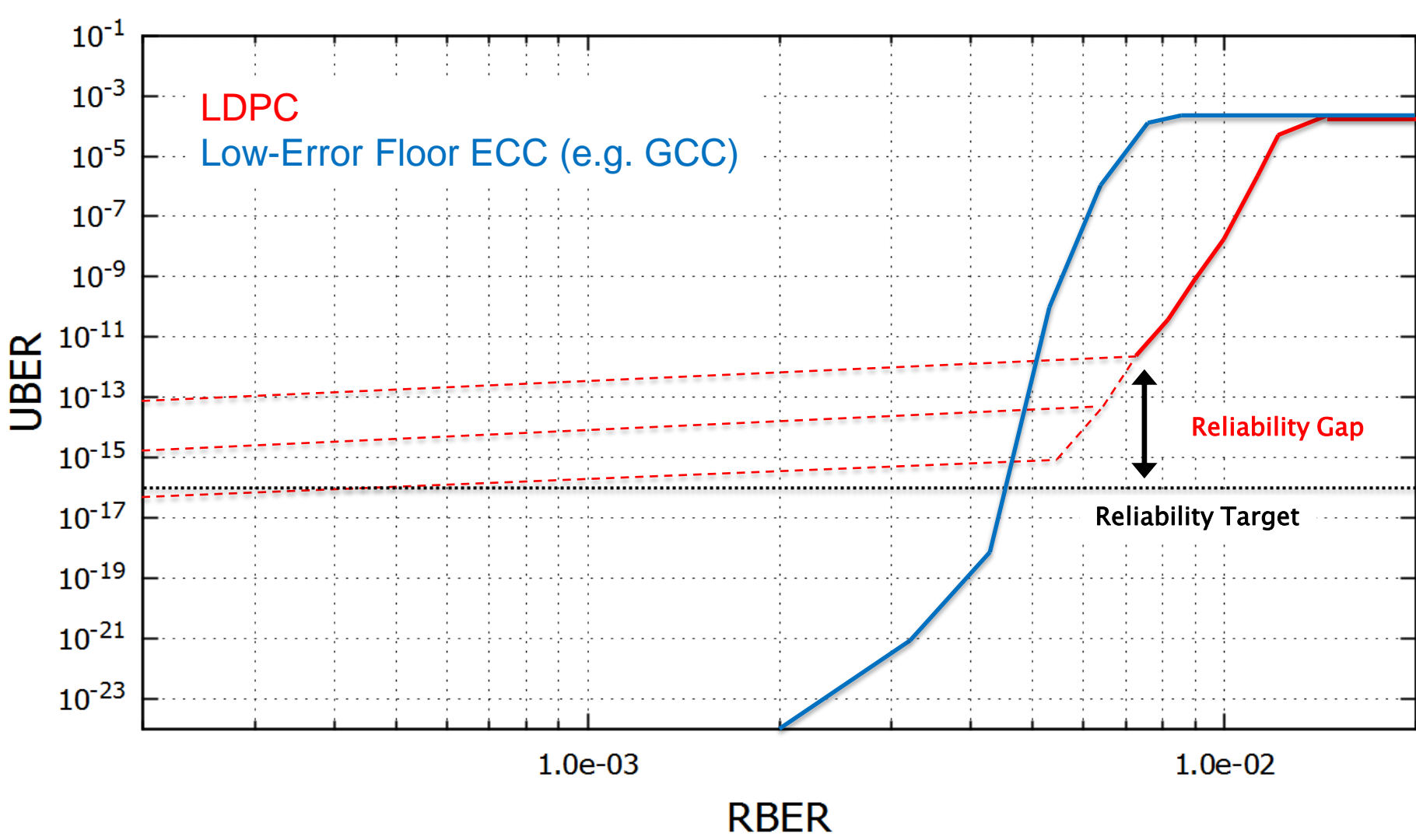
"LDPC Code Concepts and Performance on High-Density Flash Memory", Erich F. Haratsch, Flash Memory Summit 2014













# RAID vs. TempRAID

RAID (permanent)

Block A	Block B	Block C	Block D
User data	User data	User data	Parity

TempRAID

TempRAID	pSLC	pSLC	pSLC	TLC
Temporary Parity	1 page	1 page	1 page	3 pages
	1 page	1 page	1 page	3 pages
	1 page	1 page	1 page	3 pages

Keep pSLC blocks with RAID as backup until TLC block is successfully written

- WAF increase
- Performance impact
- RAID is not always the solution



# RAID vs. TempRAID

Protection Mechanism	Capacity Impact	Recovery Time	Protection Strength
RAID (3:1)	High	Medium	High
RAID (127:1)	Medium	Large	Medium
Read-Verify (temporary SLC RAID)	None	Small	High (if low error-floor ECC is used)



# Summary

- Pushing ECC performance to higher RBER may introduce a higher error floor
- RAID as countermeasure to higher UBER is costly (WAF, capacity, performance)
- Low-Error-Floor ECC (e.g. GCC)
  - Allows cheaper and reliable countermeasure (Read-Verify)
  - Allows different/less-overhead RAID structures





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# Final Thoughts...

Your key take away for the summit

- Watch for the error floor
- Is UBER plotted down to  $10^{-16}$  and beyond?
- Don't trust dotted lines – those may be based on assumptions



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*“Small things make perfection, but  
perfection is no small thing”*

– Henry Royce –



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# The secret to Designing Reliable Storage Systems

*Additional Information*

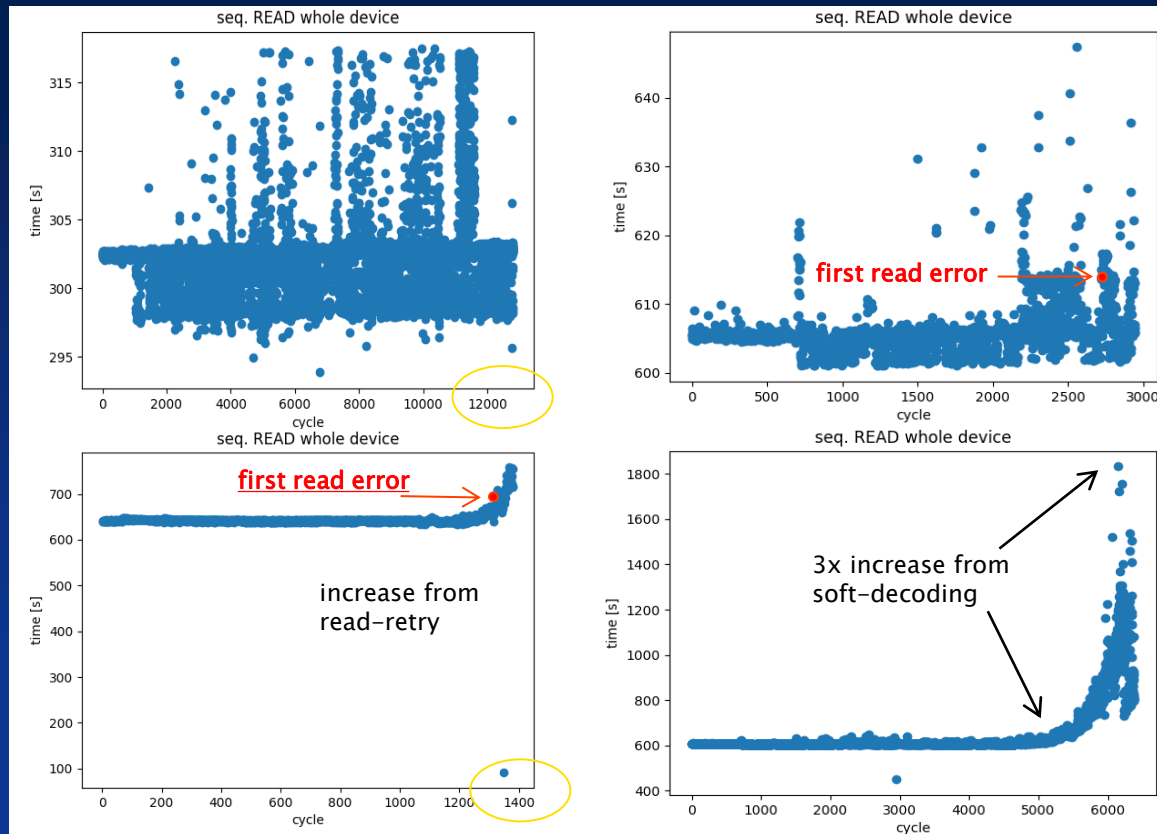




# System Level Reliability Tests

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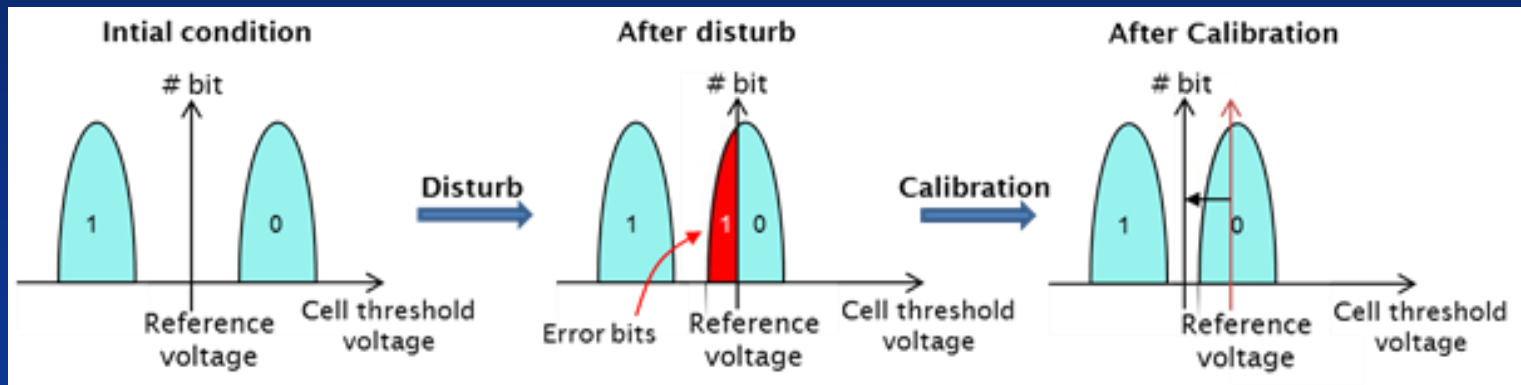
- Subsequent full drive writes (cycles) / drive reads (drive reads plotted in [s])
- Read errors are tracked, first one is highlighted
- Test stops at first failed write command
- 10x difference in lifetime of different SSDs!





# Calibration

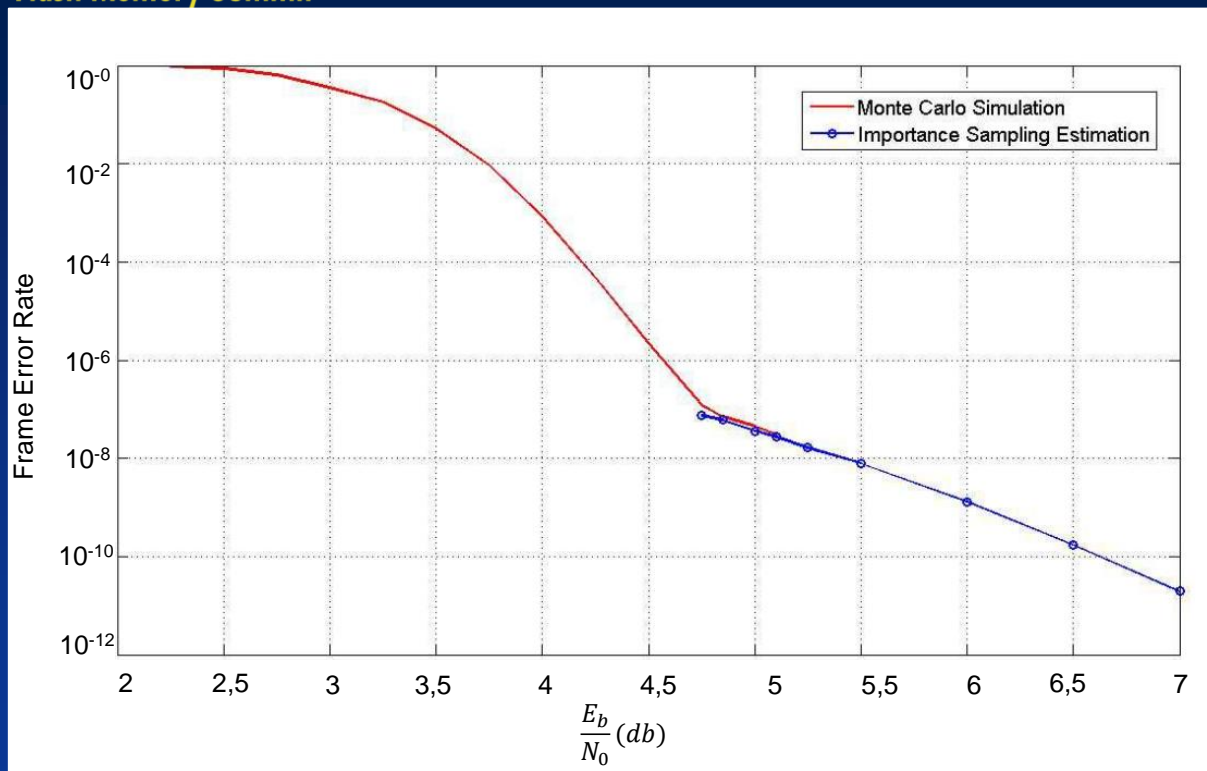
Calibration can be carried out by firmware in configurable intervals during operation







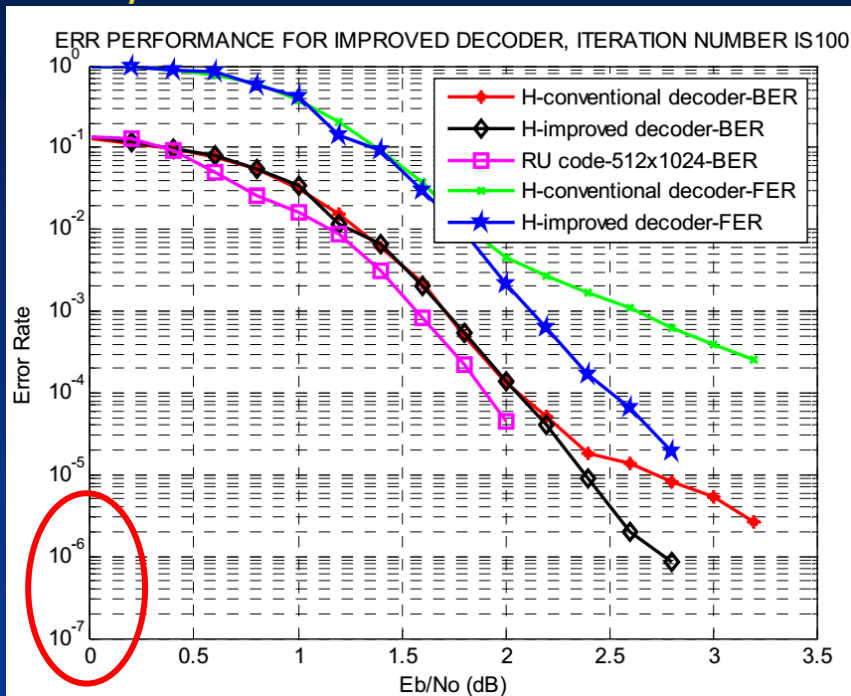
# Error Correction



- LDPC codes are not simulated down to JEDEC specified rates ( $= 10^{-16}$  for enterprise), but only down to  $\sim 10^{-10}$
- For the further trend methods like „importance sampling“ are used where a small subset of the codewords is used for estimation
- This educated guess is an orientation but nothing that can be relied on!



# Error Correction



"Analysis of Error-Prone Patterns for LDPC Codes under Belief Propagation Decoding", Huanlin Li, Yanyan Cao, Jeffrey C. Dill, The 2010 Military Communications Conference

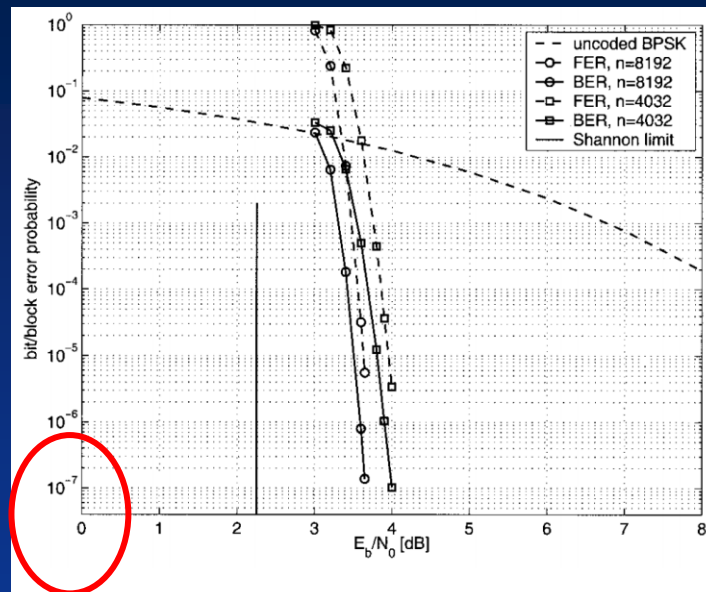


Fig. 2. Error performances of the (8192,6754) RS-based Gallager (6,32)-regular LDPC code with construction field  $GF(2^8)$ , and the (4032,3307) RS-based Gallager (60,63)-regular quasi-cyclic LDPC code with construction field  $GF(2^6)$ .

"A Class of Low-Density Parity-Check Codes Constructed Based on Reed-Solomon Codes With Two Information Symbols", Ivana Djurdjevic, Jun Xu, Khaled Abdel-Ghaffar, Member, IEEE, and Shu Lin, Fellow, IEEE, IEEE COMMUNICATIONS LETTERS, VOL. 7, NO. 7, JULY 2003



# Error Correction

- LDPC
  - High performance
  - Error-floor unknown – estimation only (e.g. importance sampling)
  - Full simulation not feasible
  - Many different “quality” grades depending on implementation and alignment to specific Flash technology and channel model
- Generalized Concatenated Code (GCC)
  - High correction performance
  - Error-floor: analytical determination possible
  - Low-Error Floor
  - Guaranteed correction capability



# UBER

- Two definitions
  - Scientific: Uncorrectable Bit Error Rate – a statistic measure of the probability of one erroneous bit after processing in the the ECC unit (module level).
  - JEDEC:  $UBER = \frac{\text{number of data errors (sectors)}}{\text{number of bits read}}$  during the TBW rating limit of the drive (sector errors of the whole system).
  - Large difference between the two depending on the ECC frame size and system sector size



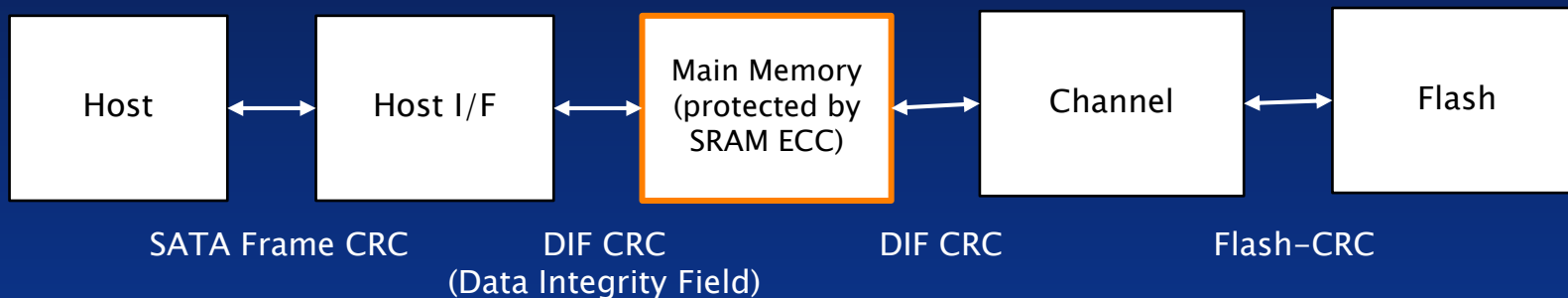
# Reliability Enhancement Techniques

Technique	Impact on Average Read Performance	Impact on Trail Performance (Read)	WAF	Management Overhead
ECC (hard-decision)	Negligible	None	Negligible	None
ECC (soft-decision)	None	High	Negligible	Negligible
Read Retry	None	High	None	Voltage levels
Flash Calibration	Low	High	None	None
RAID (3:1)	High (depending on error floor)	Medium	High	Medium
RAID (127:1)	Low (depending on error floor)	High	Medium	Low
Temporary RAID (e.g. Read-Verify)	None	None	Medium	Medium
Dynamic Data-Refresh	None	None	Low	Low





# E2E Data-Path Protection

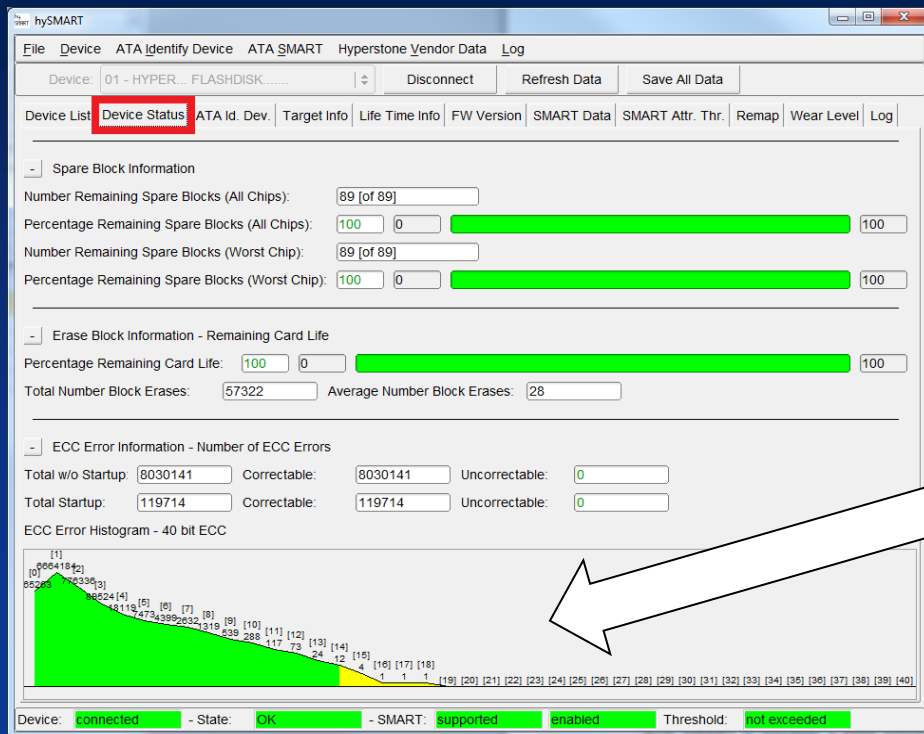


- Protection against radiation (single event effects)
- Detection & correction of errors in the main memory
- Comprehensive protection of the complete datapath



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# RBER – Lifetime Monitoring



With the Hyperstone **hySMART** tool you can monitor the corrected bit errors during lifetime to be confident your system works within operating conditions and to predict lifetime for your specific use-case and mission profile.



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# hyReliability FlashXE<sup>®</sup>

## FlashXE<sup>®</sup>



eXtended Endurance – Hardware and Firmware Features

Qualification

Near Miss ECC

Dynamic Data-Refresh

Calibration

Read Retry

Low-error floor  
ECC

Read Disturb  
Management

RAID

Read Verify